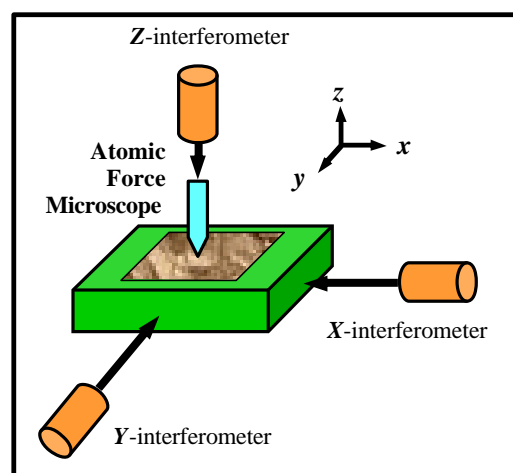


**Federal Agency on Technical Regulating and Metrology  
(Rostekhnregulirovanie)**

**CENTER FOR SURFACE AND VACUUM RESEARCH**

**Reference 3D Laser Interferometric Nanodisplacement  
Measuring System**

Reference standard system, based on atomic force microscope of singularly design with laser interferometric nanodisplacement meters for surface nanorelief and linear displacement measurement along 3 coordinates in microelectronic, nanotechnology and micromechanic and certification the reference standards for calibration scanning electron and atomic force microscopes.



**General technical data**

Nanodisplacement measurement	along X, Y, Z
Discreteness of step along X & Y :	0.1 nm
Range of linear displacement:	
along X & Y :	1 ÷ 3000 nm
along Z :	1 ÷ 1000 nm
Accuracy:	
along X & Y :	0.5 nm
along Z :	0.5 ÷ 3 nm

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